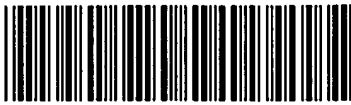


Search Notes



Application/Control No.

10/750,619

Examiner

Sam K. Ahn

Applicant(s)/Patent under Reexamination

JALLOUL ET AL.

Art Unit

2611

SEARCHED

Class	Subclass	Date	Examiner
375	316, 317	3/30	<i>Am</i>
329	318, 349, 353		
327	37, 80		
379	112.04		
702	193		
370	280		
455	67.11, 296, 522	3/30	<i>Am</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
EAST inventor search, keyword & citation search	3/30	<i>Am</i>
IEEE and google keyword & citation search	3/30	<i>Am</i>